



# FQD12P10 / FQU12P10

### 100V P-Channel MOSFET

#### **General Description**

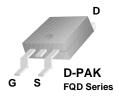
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

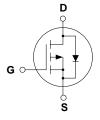
#### **Features**

- -9.4A, -100V,  $R_{DS(on)}$  = 0.29 $\Omega$  @V<sub>GS</sub> = -10 V Low gate charge ( typical 21 nC)
- Low Crss (typical 65 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- · RoHS Compliant









### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

| Symbol                            | Parameter  |          | FQD12P10 / FQU12P10 | Units |
|-----------------------------------|--|----------|---------------------|-------|
| V <sub>DSS</sub>                  | Drain-Source Voltage   |          | -100                | V     |
| I <sub>D</sub>                    | Drain Current - Continuous (T <sub>C</sub> = 25°C) - Continuous (T <sub>C</sub> = 100°C) |          | -9.4                | Α     |
|                                   |  |          | -6.0                | Α     |
| I <sub>DM</sub>                   | Drain Current - Pulsed   | (Note 1) | -37.6               | Α     |
| $V_{GSS}$                         | Gate-Source Voltage  |          | ± 30                | V     |
| E <sub>AS</sub>                   | Single Pulsed Avalanche Energy   | (Note 2) | 370                 | mJ    |
| I <sub>AR</sub>                   | Avalanche Current  | (Note 1) | -9.4                | А     |
| E <sub>AR</sub>                   | Repetitive Avalanche Energy  | (Note 1) | 5.0                 | mJ    |
| dv/dt                             | Peak Diode Recovery dv/dt  | (Note 3) | -6.0                | V/ns  |
| P <sub>D</sub>                    | Power Dissipation (T <sub>A</sub> = 25°C) *  |          | 2.5                 | W     |
|                                   | Power Dissipation (T <sub>C</sub> = 25°C)  |          | 50                  | W     |
|                                   | - Derate above 25°C  |          | 0.4                 | W/°C  |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Temperature Range  |          | -55 to +150         | °C    |
| T <sub>L</sub>                    | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds            |          | 300                 | °C    |

### **Thermal Characteristics**

| Symbol   | Parameter                               | Тур | Max | Units |
|--|---|-----|-----|-------|
| R <sub>θJC</sub> Thermal Resistance, Junction-to-Case      |   |     | 2.5 | °C/W  |
| R <sub>θJA</sub> Thermal Resistance, Junction-to-Ambient * |   |     | 50  | °C/W  |
| $R_{\theta JA}$  | Thermal Resistance, Junction-to-Ambient |     | 110 | °C/W  |

| Symbol   | Parameter Test Conditions   |  | Min  | Тур              | Max              | Units    |
|--|---|--|------|------------------|------------------|----------|
| Off Cha  | racteristics  |  |      |                  |                  |          |
| BV <sub>DSS</sub>                                  | Drain-Source Breakdown Voltage  | $V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$                         | -100 |                  |                  | V        |
| $\Delta BV_{DSS}$ / $\Delta T_{J}$                 | Breakdown Voltage Temperature<br>Coefficient  | $I_D = -250 \mu\text{A}$ , Referenced to 25°C                          | ;    | -0.1             |                  | V/°C     |
| I <sub>DSS</sub>                                   | Zero Gate Voltage Drain Current   | V <sub>DS</sub> = -100 V, V <sub>GS</sub> = 0 V                        |      |                  | -1               | μΑ       |
|  |   | V <sub>DS</sub> = -80 V, T <sub>C</sub> = 125°C                        |      | -                | -10              | μΑ       |
| I <sub>GSSF</sub>                                  | Gate-Body Leakage Current, Forward  | V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V                         |      |                  | -100             | nA       |
| I <sub>GSSR</sub>                                  | Gate-Body Leakage Current, Reverse V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V    |  |      |                  | 100              | nA       |
| On Cha   | racteristics  |  |      |                  |                  |          |
| V <sub>GS(th)</sub>                                | Gate Threshold Voltage  | $V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$                            | -2.0 |                  | -4.0             | V        |
| R <sub>DS(on)</sub>                                | Static Drain-Source On-Resistance  V <sub>GS</sub> = -10 V, I <sub>D</sub> = -4.7 A |  |      | 0.24             | 0.29             | Ω        |
| 9 <sub>FS</sub>                                    | Forward Transconductance  | V <sub>DS</sub> = -40 V, I <sub>D</sub> = -4.7 A (Note 4)              |      | 6.3              |                  | S        |
| C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> | Input Capacitance Output Capacitance Reverse Transfer Capacitance                   | $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$<br>f = 1.0  MHz        |      | 620<br>220<br>65 | 800<br>290<br>85 | pF<br>pF |
|  | ng Characteristics  |  |      |                  |                  | P.       |
| t <sub>d(on)</sub>                                 | Turn-On Delay Time  | alay Timo  |      | 15               | 40               | ns       |
| t <sub>r</sub>                                     | Turn-On Rise Time   | $V_{DD} = -50 \text{ V}, I_{D} = -11.5 \text{ A},$ $R_{G} = 25 \Omega$ |      | 160              | 330              | ns       |
| t <sub>d(off)</sub>                                | Turn-Off Delay Time   | 11.6 - 20 32   |      | 35               | 80               | ns       |
| t <sub>f</sub>                                     | Turn-Off Fall Time  | (Note 4, 5   | )    | 60               | 130              | ns       |
| Qg   | Total Gate Charge   | V <sub>DS</sub> = -80 V, I <sub>D</sub> = -11.5 A,                     |      | 21               | 27               | nC       |
| Q <sub>gs</sub>                                    | Gate-Source Charge  | V <sub>GS</sub> = -10 V  |      | 4.6              |                  | nC       |
| Q <sub>gd</sub>                                    | Gate-Drain Charge   | (Note 4, 5   | )    | 11.5             |                  | nC       |
| Drain-S  | ource Diode Characteristics a   | nd Maximum Ratings   |      |                  |                  |          |
| I <sub>S</sub>                                     | Maximum Continuous Drain-Source Diode Forward Current                               |  |      |                  | -9.4             | Α        |
| I <sub>SM</sub>                                    | Maximum Pulsed Drain-Source Diode Forward Current                                   |  |      |                  | -37.6            | Α        |
| V <sub>SD</sub>                                    | Drain-Source Diode Forward Voltage  | $V_{GS} = 0 \text{ V}, I_{S} = -9.4 \text{ A}$                         |      |                  | -4.0             | V        |
| t <sub>rr</sub>                                    | Reverse Recovery Time   | $V_{GS} = 0 \text{ V}, I_{S} = -11.5 \text{ A},$                       |      | 110              |                  | ns       |
| Q <sub>rr</sub>                                    | Reverse Recovery Charge   | $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)                       |      | 0.47             |                  | μC       |

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 6.3mH,  $I_{AS}$  = -9.4A,  $V_{DD}$  = -25V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C 3.  $I_{SD}$   $\leq$  -11.5A, di/dt  $\leq$  300A/ $\mu$ s,  $V_{DD}$   $\leq$  BV $_{DSS}$ , Starting  $T_{J}$  = 25°C 4. Pulse Test : Pulse width  $\leq$  300 $\mu$ s, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

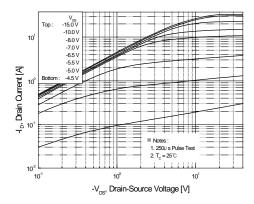


Figure 1. On-Region Characteristics

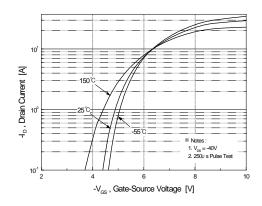


Figure 2. Transfer Characteristics

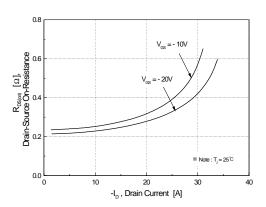


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

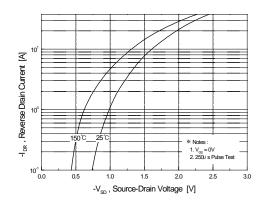


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

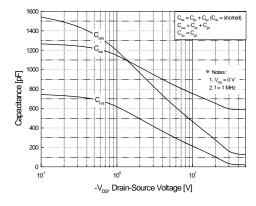


Figure 5. Capacitance Characteristics

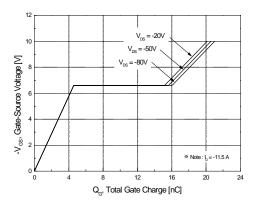
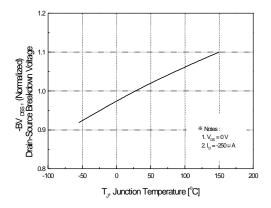


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



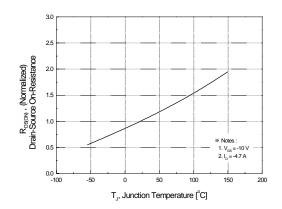
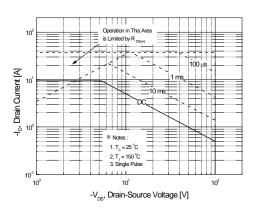


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



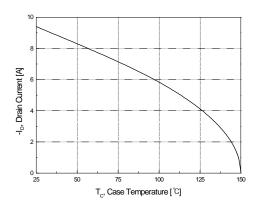


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

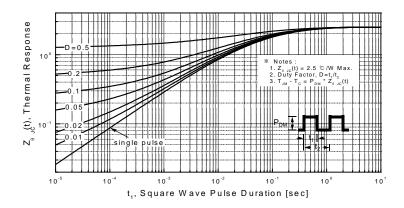
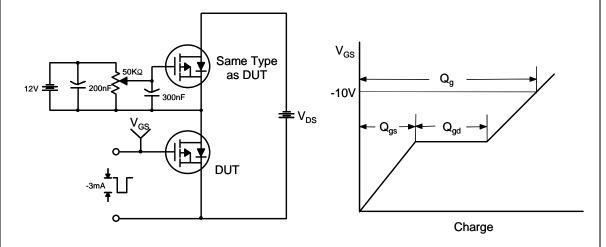


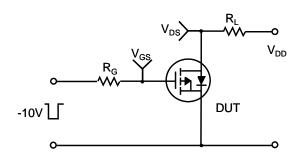
Figure 11. Transient Thermal Response Curve

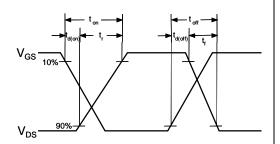
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### **Gate Charge Test Circuit & Waveform**

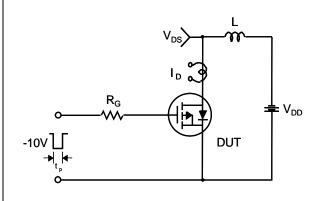


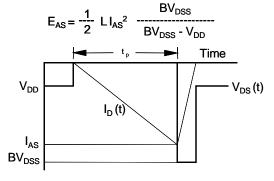
### **Resistive Switching Test Circuit & Waveforms**



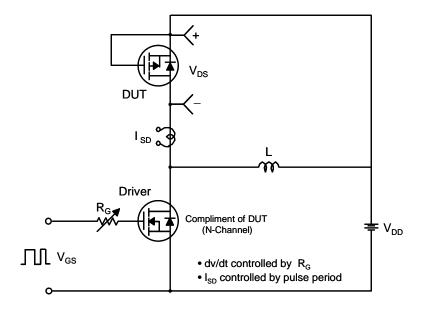


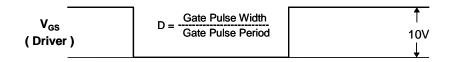
### **Unclamped Inductive Switching Test Circuit & Waveforms**

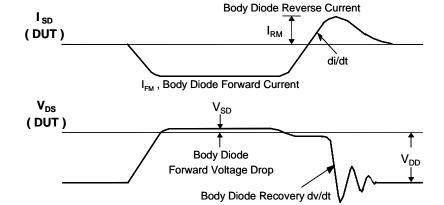




#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



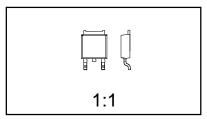




# **Package Dimensions**

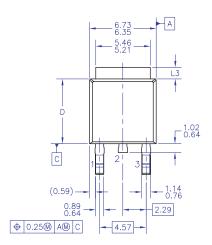
# TO-252 (DPAK) (FS PKG Code 36)

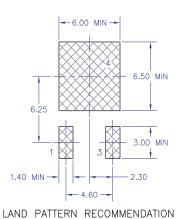


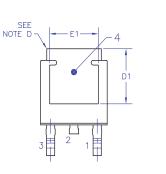


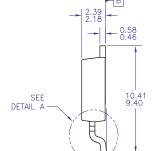
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

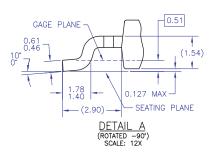
Part Weight per unit (gram): 0.33











△ 0.10 B

- NOTES: UNLESS OTHERWISE SPECIFIED

  A) ALL DIMENSIONS ARE IN MILLIMETERS.

  B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

  C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

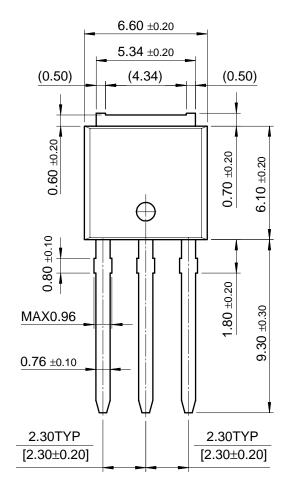
  - HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

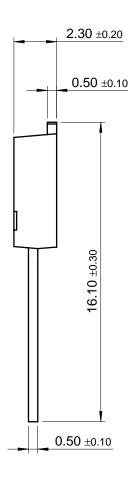
    DIMENSIONS L3,D,E1&D1 TABLE:

|    | OPTION AA | OPTION AB |
|----|-----------|-----------|
| L3 | 0.89-1.27 | 1.52-2.03 |
| D  | 5.97-6.22 | 5.33-5.59 |
| E1 | 4.32 MIN  | 3.81 MIN  |
| D1 | 5.21 MIN  | 4.57 MIN  |



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Dimensions in Millimeters





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